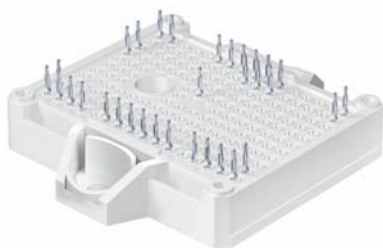


# SK100MLI07S5TD1E2



SEMITOP®E2

## 3-Level NPC

### SK100MLI07S5TD1E2

#### Features\*

- Optimized design for superior thermal performance
- Low inductive design
- Press-Fit contact technology
- Split IGBT gates for optimized driving
- 650V Trench5 IGBT (S5)
- Rapid switching diode technology
- Integrated NTC temperature sensor
- UL recognized file no. E 63 532

#### Typical Applications

- UPS
- Energy Storage Systems
- Solar

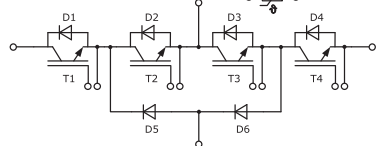
#### Remarks\*

- Recommended  $T_{j,op} = -40 \dots +150 \text{ }^\circ\text{C}$
- IGBTs characteristics are valid for paralleled chips (split gates connected)
- IGBT1: outer IGBTs T1 & T4
- IGBT2: inner IGBTs T2 & T3
- Diode1: outer Diodes D1 & D4
- Diode2: inner Diodes D2 & D3
- Diode5: clamping Diodes D5 & D6

#### Footnotes

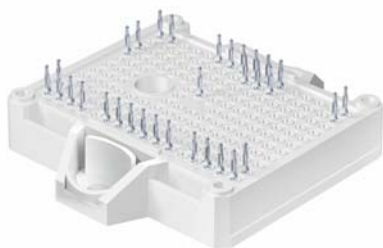
<sup>1)</sup> Please find further technical information on the SEMIKRON website.

Absolute Maximum Ratings			
Symbol	Conditions	Values	Unit
<b>IGBT1</b>			
$V_{CES}$	$T_j = 25 \text{ }^\circ\text{C}$	650	V
$I_C$	$\lambda_{paste}=0.8 \text{ W/(mK)}$	$T_s = 25 \text{ }^\circ\text{C}$	96
	$T_j = 175 \text{ }^\circ\text{C}$	$T_s = 70 \text{ }^\circ\text{C}$	76
$I_C$	$\lambda_{paste}=2.5 \text{ W/(mK)}$	$T_s = 25 \text{ }^\circ\text{C}$	113
	$T_j = 175 \text{ }^\circ\text{C}$	$T_s = 70 \text{ }^\circ\text{C}$	90
$I_{Cnom}$		100	A
$I_{CRM}$		200	A
$V_{GES}$		-20 ... 20	V
$t_{psc}$	$V_{CC} = 360 \text{ V}, V_{GE} \leq 15 \text{ V}, T_j = 150 \text{ }^\circ\text{C}, V_{CES} \leq 650 \text{ V}$	not capable	$\mu\text{s}$
$T_j$		-40 ... 175	$^\circ\text{C}$
<b>IGBT2</b>			
$V_{CES}$	$T_j = 25 \text{ }^\circ\text{C}$	650	V
$I_C$	$\lambda_{paste}=0.8 \text{ W/(mK)}$	$T_s = 25 \text{ }^\circ\text{C}$	96
	$T_j = 175 \text{ }^\circ\text{C}$	$T_s = 70 \text{ }^\circ\text{C}$	76
$I_C$	$\lambda_{paste}=2.5 \text{ W/(mK)}$	$T_s = 25 \text{ }^\circ\text{C}$	113
	$T_j = 175 \text{ }^\circ\text{C}$	$T_s = 70 \text{ }^\circ\text{C}$	90
$I_{Cnom}$		100	A
$I_{CRM}$		200	A
$V_{GES}$		-20 ... 20	V
$t_{psc}$	$V_{CC} = 360 \text{ V}, V_{GE} \leq 15 \text{ V}, T_j = 150 \text{ }^\circ\text{C}, V_{CES} \leq 650 \text{ V}$	not capable	$\mu\text{s}$
$T_j$		-40 ... 175	$^\circ\text{C}$
<b>Diode1</b>			
$V_{RRM}$	$T_j = 25 \text{ }^\circ\text{C}$	650	V
$I_F$	$\lambda_{paste}=0.8 \text{ W/(mK)}$	$T_s = 25 \text{ }^\circ\text{C}$	107
	$T_j = 175 \text{ }^\circ\text{C}$	$T_s = 70 \text{ }^\circ\text{C}$	82
$I_F$	$\lambda_{paste}=2.5 \text{ W/(mK)}$	$T_s = 25 \text{ }^\circ\text{C}$	127
	$T_j = 175 \text{ }^\circ\text{C}$	$T_s = 70 \text{ }^\circ\text{C}$	98
$I_{FRM}$		200	A
$I_{FSM}$	10 ms, sin 180°, $T_j = 25 \text{ }^\circ\text{C}$	630	A
$T_j$		-40 ... 175	$^\circ\text{C}$
<b>Diode2</b>			
$V_{RRM}$	$T_j = 25 \text{ }^\circ\text{C}$	650	V
$I_F$	$\lambda_{paste}=0.8 \text{ W/(mK)}$	$T_s = 25 \text{ }^\circ\text{C}$	107
	$T_j = 175 \text{ }^\circ\text{C}$	$T_s = 70 \text{ }^\circ\text{C}$	82
$I_F$	$\lambda_{paste}=2.5 \text{ W/(mK)}$	$T_s = 25 \text{ }^\circ\text{C}$	127
	$T_j = 175 \text{ }^\circ\text{C}$	$T_s = 70 \text{ }^\circ\text{C}$	98
$I_{FRM}$		200	A
$I_{FSM}$	10 ms, sin 180°, $T_j = 25 \text{ }^\circ\text{C}$	630	A
$T_j$		-40 ... 175	$^\circ\text{C}$



MLI-T

# SK100MLI07S5TD1E2



SEMITOP®E2

## 3-Level NPC

### SK100MLI07S5TD1E2

#### Features\*

- Optimized design for superior thermal performance
- Low inductive design
- Press-Fit contact technology
- Split IGBT gates for optimized driving
- 650V Trench5 IGBT (S5)
- Rapid switching diode technology
- Integrated NTC temperature sensor
- UL recognized file no. E 63 532

#### Typical Applications

- UPS
- Energy Storage Systems
- Solar

#### Remarks\*

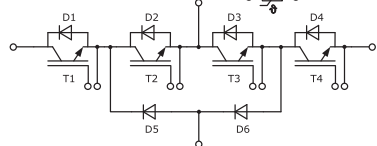
- Recommended  $T_{j,op} = -40 \dots +150 \text{ °C}$
- IGBTs characteristics are valid for paralleled chips (split gates connected)
- IGBT1: outer IGBTs T1 & T4
- IGBT2: inner IGBTs T2 & T3
- Diode1: outer Diodes D1 & D4
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- Diode5: clamping Diodes D5 & D6

#### Footnotes

<sup>1)</sup> Please find further technical information on the SEMIKRON website.

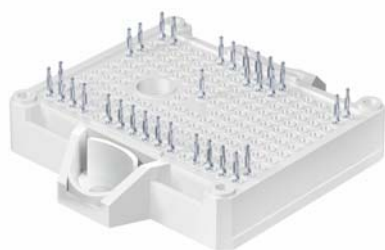
Absolute Maximum Ratings				
Symbol	Conditions	Values	Unit	
<b>Diode5</b>				
$V_{RRM}$	$T_j = 25 \text{ °C}$	650	V	
$I_F$	$\lambda_{paste} = 0.8 \text{ W/(mK)}$	$T_s = 25 \text{ °C}$	97	A
	$T_j = 175 \text{ °C}$	$T_s = 70 \text{ °C}$	77	A
$I_F$	$\lambda_{paste} = 2.5 \text{ W/(mK)}$	$T_s = 25 \text{ °C}$	114	A
	$T_j = 175 \text{ °C}$	$T_s = 70 \text{ °C}$	90	A
$I_{FRM}$		200	A	
$I_{FSM}$	10 ms, sin 180°, $T_j = 25 \text{ °C}$	540	A	
$T_j$		-40 ... 175	°C	
<b>Module</b>				
$I_{t(RMS)}$	$\Delta T_{terminal}$ at PCB joint = 30 K, per pin	30	A	
$T_{stg}$	module without TIM	-40 ... 125	°C	
$V_{isol}$	AC, sinusoidal, t = 1 min	2500	V	

Characteristics					
Symbol	Conditions	min.	typ.	max.	Unit
<b>IGBT1</b>					
$V_{CE(sat)}$	$I_C = 100 \text{ A}$ $V_{GE} = 15 \text{ V}$ chiplevel	$T_j = 25 \text{ °C}$	1.35	1.75	V
		$T_j = 150 \text{ °C}$	1.56	2.06	V
$V_{CE0}$	chiplevel	$T_j = 25 \text{ °C}$	0.92	1.02	V
		$T_j = 150 \text{ °C}$	0.82	0.97	V
$r_{CE}$	$V_{GE} = 15 \text{ V}$ chiplevel	$T_j = 25 \text{ °C}$	4.3	7.3	mΩ
		$T_j = 150 \text{ °C}$	7.4	11	mΩ
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 1 \text{ mA}$	3.2	4	4.8	V
$I_{CES}$	$V_{GE} = 0 \text{ V}, V_{CE} = 650 \text{ V}, T_j = 25 \text{ °C}$			0.45	mA
$C_{ies}$	$V_{CE} = 25 \text{ V}$ $V_{GE} = 0 \text{ V}$	$f = 1 \text{ MHz}$	6.2		nF
$C_{oes}$		$f = 1 \text{ MHz}$	0.176		nF
$C_{res}$		$f = 1 \text{ MHz}$	0.024		nF
$Q_G$	$V_{GE} = -15 \text{ V} \dots +15 \text{ V}$		480		nC
$R_{Gint}$	$T_j = 25 \text{ °C}$		0		Ω
$t_{d(on)}$	$V_{CE} = 300 \text{ V}$ $I_C = 100 \text{ A}$	$T_j = 150 \text{ °C}$	27		ns
$t_r$		$T_j = 150 \text{ °C}$	22		ns
$E_{on}$	$V_{GE} = +15/-15 \text{ V}$ $R_{G on} = 1.5 \text{ Ω}$	$T_j = 150 \text{ °C}$	0.36		mJ
$t_{d(off)}$	$R_{G off} = 1.5 \text{ Ω}$	$T_j = 150 \text{ °C}$	107		ns
$t_f$	$di/dt_{on} = 4170 \text{ A/μs}$	$T_j = 150 \text{ °C}$	29		ns
	$di/dt_{off} = 2930 \text{ A/μs}$				
$E_{off}$	$dv/dt = 7710 \text{ V/μs}$	$T_j = 150 \text{ °C}$	1.63		mJ
$R_{th(j-s)}$	per IGBT, $\lambda_{paste} = 0.8 \text{ W/(mK)}$		0.74		K/W
$R_{th(j-s)}$	per IGBT, $\lambda_{paste} = 2.5 \text{ W/(mK)}$		0.57		K/W



MLI-T

# SK100MLI07S5TD1E2



SEMITOP®E2

## 3-Level NPC

### SK100MLI07S5TD1E2

#### Features\*

- Optimized design for superior thermal performance
- Low inductive design
- Press-Fit contact technology
- Split IGBT gates for optimized driving
- 650V Trench5 IGBT (S5)
- Rapid switching diode technology
- Integrated NTC temperature sensor
- UL recognized file no. E 63 532

#### Typical Applications

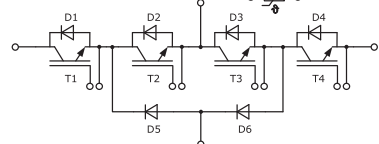
- UPS
- Energy Storage Systems
- Solar

#### Remarks\*

- Recommended  $T_{j,op} = -40 \dots +150 \text{ }^\circ\text{C}$
- IGBTs characteristics are valid for paralleled chips (split gates connected)
- IGBT1: outer IGBTs T1 & T4
- IGBT2: inner IGBTs T2 & T3
- Diode1: outer Diodes D1 & D4
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- Diode5: clamping Diodes D5 & D6

#### Footnotes

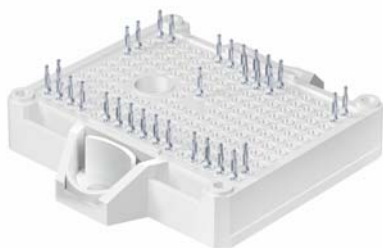
<sup>1)</sup> Please find further technical information on the SEMIKRON website.



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Characteristics			min.	typ.	max.	Unit
Symbol	Conditions					
<b>IGBT2</b>						
$V_{CE(sat)}$	$I_C = 100 \text{ A}$ $V_{GE} = 15 \text{ V}$ chipllevel	$T_j = 25 \text{ }^\circ\text{C}$	1.35	1.75		V
		$T_j = 150 \text{ }^\circ\text{C}$	1.56	2.06		V
$V_{CE0}$	chipllevel	$T_j = 25 \text{ }^\circ\text{C}$	0.92	1.02		V
		$T_j = 150 \text{ }^\circ\text{C}$	0.82	0.97		V
$r_{CE}$	$V_{GE} = 15 \text{ V}$ chipllevel	$T_j = 25 \text{ }^\circ\text{C}$	4.3	7.3		m $\Omega$
		$T_j = 150 \text{ }^\circ\text{C}$	7.4	11		m $\Omega$
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 1 \text{ mA}$		3.2	4	4.8	V
$I_{CES}$	$V_{GE} = 0 \text{ V}, V_{CE} = 650 \text{ V}, T_j = 25 \text{ }^\circ\text{C}$				0.45	mA
$C_{ies}$	$V_{CE} = 25 \text{ V}$ $V_{GE} = 0 \text{ V}$	$f = 1 \text{ MHz}$		6.2		nF
$C_{oes}$		$f = 1 \text{ MHz}$		0.176		nF
$C_{res}$		$f = 1 \text{ MHz}$		0.024		nF
$Q_G$	$V_{GE} = -15 \text{ V} \dots +15 \text{ V}$			480		nC
$R_{Gint}$	$T_j = 25 \text{ }^\circ\text{C}$			0		$\Omega$
$t_{d(on)}$	$V_{CC} = 300 \text{ V}$	$T_j = 150 \text{ }^\circ\text{C}$		24		ns
$t_r$	$I_C = 100 \text{ A}$	$T_j = 150 \text{ }^\circ\text{C}$		17		ns
$E_{on}$	$V_{GE} = +15/-15 \text{ V}$ $R_{G on} = 1 \text{ }^\circ\Omega$	$T_j = 150 \text{ }^\circ\text{C}$		0.36		mJ
$t_{d(off)}$	$R_{G off} = 1 \text{ }^\circ\Omega$	$T_j = 150 \text{ }^\circ\text{C}$		103		ns
$t_f$	$di/dt_{on} = 4330 \text{ A}/\mu\text{s}$	$T_j = 150 \text{ }^\circ\text{C}$		30		ns
$E_{off}$	$di/dt_{off} = 2520 \text{ A}/\mu\text{s}$ $dv/dt = 7220 \text{ V}/\mu\text{s}$	$T_j = 150 \text{ }^\circ\text{C}$		1.77		mJ
$R_{th(j-s)}$	per IGBT, $\lambda_{paste} = 0.8 \text{ W}/(\text{mK})$			0.74		K/W
$R_{th(j-s)}$	per IGBT, $\lambda_{paste} = 2.5 \text{ W}/(\text{mK})$			0.57		K/W
<b>Diode1</b>						
$V_F = V_{EC}$	$I_F = 100 \text{ A}$ chipllevel	$T_j = 25 \text{ }^\circ\text{C}$	1.55	1.82		V
		$T_j = 150 \text{ }^\circ\text{C}$	1.45	1.75		V
$V_{F0}$	chipllevel	$T_j = 25 \text{ }^\circ\text{C}$	1.10	1.32		V
		$T_j = 150 \text{ }^\circ\text{C}$	0.95	1.14		V
$r_F$	chipllevel	$T_j = 25 \text{ }^\circ\text{C}$	4.5	5.0		m $\Omega$
		$T_j = 150 \text{ }^\circ\text{C}$	5.0	6.1		m $\Omega$
$I_{RRM}$	$I_F = 100 \text{ A}$	$T_j = 150 \text{ }^\circ\text{C}$		107		A
$Q_{rr}$	$di/dt_{off} = 4690 \text{ A}/\mu\text{s}$ $V_R = 300 \text{ V}$	$T_j = 150 \text{ }^\circ\text{C}$		6.75		$\mu\text{C}$
$E_{rr}$	$V_{GE} = +15/-15 \text{ V}$	$T_j = 150 \text{ }^\circ\text{C}$		1.77		mJ
$R_{th(j-s)}$	per Diode, $\lambda_{paste} = 0.8 \text{ W}/(\text{mK})$			0.79		K/W
$R_{th(j-s)}$	per Diode, $\lambda_{paste} = 2.5 \text{ W}/(\text{mK})$			0.62		K/W
<b>Diode2</b>						
$V_F = V_{EC}$	$I_F = 100 \text{ A}$ chipllevel	$T_j = 25 \text{ }^\circ\text{C}$	1.55	1.82		V
		$T_j = 150 \text{ }^\circ\text{C}$	1.45	1.75		V
$V_{F0}$	chipllevel	$T_j = 25 \text{ }^\circ\text{C}$	1.10	1.32		V
		$T_j = 150 \text{ }^\circ\text{C}$	0.95	1.14		V
$r_F$	chipllevel	$T_j = 25 \text{ }^\circ\text{C}$	4.5	5.0		m $\Omega$
		$T_j = 150 \text{ }^\circ\text{C}$	5.0	6.1		m $\Omega$
$I_{RRM}$		$T_j = 150 \text{ }^\circ\text{C}$		-		A
$Q_{rr}$		$T_j = 150 \text{ }^\circ\text{C}$		-		$\mu\text{C}$
$E_{rr}$ <sup>1)</sup>	$V_{GE} = +15/-15 \text{ V}$	$T_j = 150 \text{ }^\circ\text{C}$		-		mJ
$R_{th(j-s)}$	per Diode, $\lambda_{paste} = 0.8 \text{ W}/(\text{mK})$			0.79		K/W
$R_{th(j-s)}$	per Diode, $\lambda_{paste} = 2.5 \text{ W}/(\text{mK})$			0.62		K/W

# SK100MLI07S5TD1E2



SEMITOP®E2

## 3-Level NPC

### SK100MLI07S5TD1E2

#### Features\*

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- Low inductive design
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- 650V Trench5 IGBT (S5)
- Rapid switching diode technology
- Integrated NTC temperature sensor
- UL recognized file no. E 63 532

#### Typical Applications

- UPS
- Energy Storage Systems
- Solar

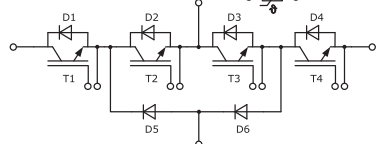
#### Remarks\*

- Recommended  $T_{j,op} = -40 \dots +150 \text{ °C}$
- IGBTs characteristics are valid for paralleled chips (split gates connected)
- IGBT1: outer IGBTs T1 & T4
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- Diode1: outer Diodes D1 & D4
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- Diode5: clamping Diodes D5 & D6

#### Footnotes

1) Please find further technical information on the SEMIKRON website.

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
<b>Diode5</b>						
$V_F = V_{EC}$	$I_F = 100 \text{ A}$	$T_j = 25 \text{ °C}$		1.35	1.92	V
		chipelevel	$T_j = 150 \text{ °C}$	1.30	1.89	V
$V_{F0}$	chipelevel	$T_j = 25 \text{ °C}$		0.90	1.10	V
		$T_j = 150 \text{ °C}$		0.71	0.94	V
$r_F$	chipelevel	$T_j = 25 \text{ °C}$		4.5	8.2	mΩ
		$T_j = 150 \text{ °C}$		5.8	9.5	mΩ
$I_{RRM}$	$I_F = 100 \text{ A}$	$T_j = 150 \text{ °C}$		115		A
$Q_{rr}$	$di/dt_{off} = 4210 \text{ A/}\mu\text{s}$ $V_R = 300 \text{ V}$	$T_j = 150 \text{ °C}$		6.45		μC
$E_{rr}$	$V_{GE} = +15/-15 \text{ V}$	$T_j = 150 \text{ °C}$		1.79		mJ
$R_{th(j-s)}$	per Diode, $\lambda_{paste} = 0.8 \text{ W/(mK)}$			0.83		K/W
$R_{th(j-s)}$	per Diode, $\lambda_{paste} = 2.5 \text{ W/(mK)}$			0.65		K/W
<b>Module</b>						
$L_{sCE1}$				10		nH
$L_{sCE2}$				12		nH
$R_{CC+EE}$			$T_s = 25 \text{ °C}$	-		mΩ
			$T_s = 150 \text{ °C}$	-		mΩ
$M_s$	to heatsink			1.6	2.3	Nm
$M_t$				-		Nm
				-		Nm
$w$				35		g
<b>Temperature Sensor</b>						
$R_{25}$	$T_r = 25 \text{ °C}$			22 ±5%		kΩ
$B_{25/50}$	$R(T) = R_{25} \exp[B_{25/50}(1/T - 1/T_{25})]$ ; $T[\text{K}]$			3950 ±3%		K



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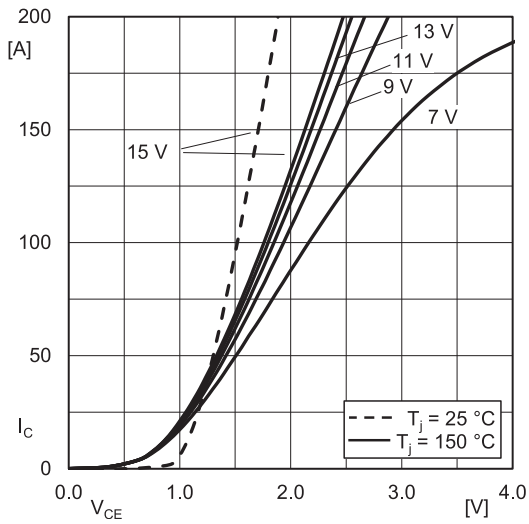


Fig. 1: Typ. IGBT1 output characteristic, incl.  $R_{CC'+EE'}$

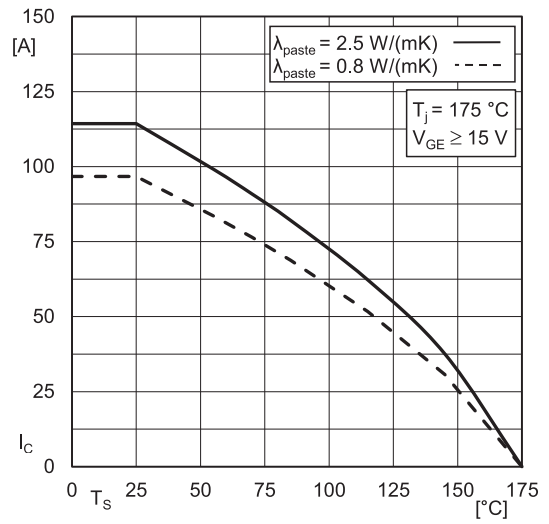


Fig. 2: IGBT1 rated current vs. Temperature  $I_C=f(T_s)$

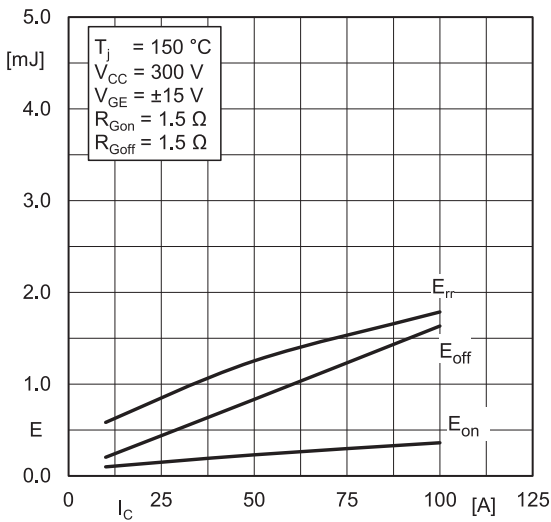


Fig. 3: Typ. IGBT1 & Diode5 turn-on /-off energy =  $f(I_C)$

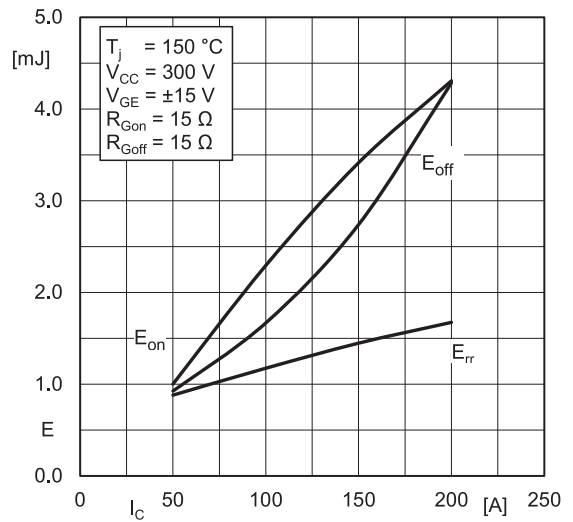


Fig. 3a: Typ. IGBT1 & Diode5 turn-on /-off energy =  $f(I_C)$

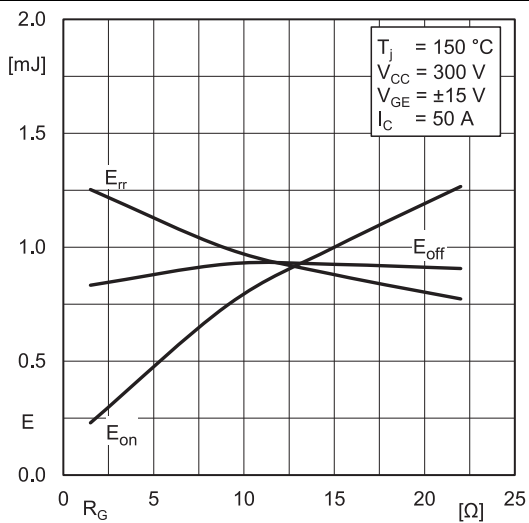


Fig. 4: Typ. IGBT1 & Diode5 turn-on /-off energy =  $f(R_G)$

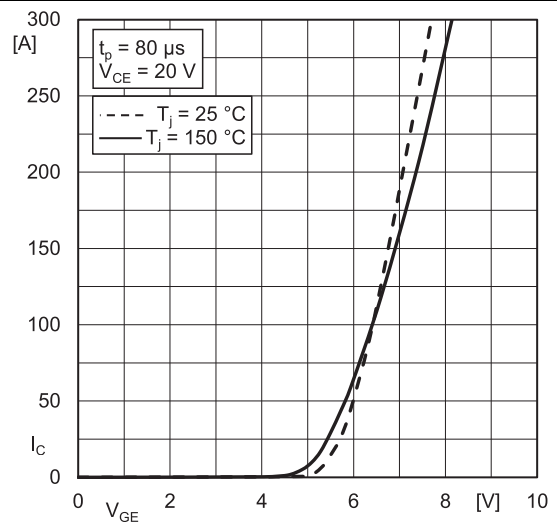


Fig. 5: Typ. IGBT1 transfer characteristic

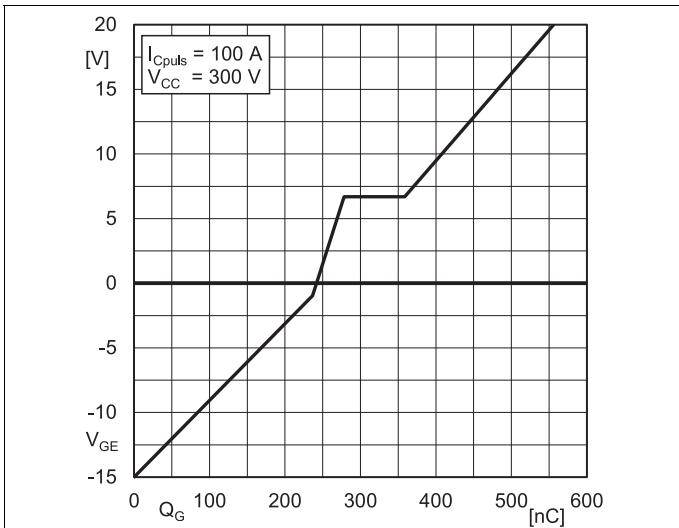


Fig. 6: Typ. IGBT1 gate charge characteristic

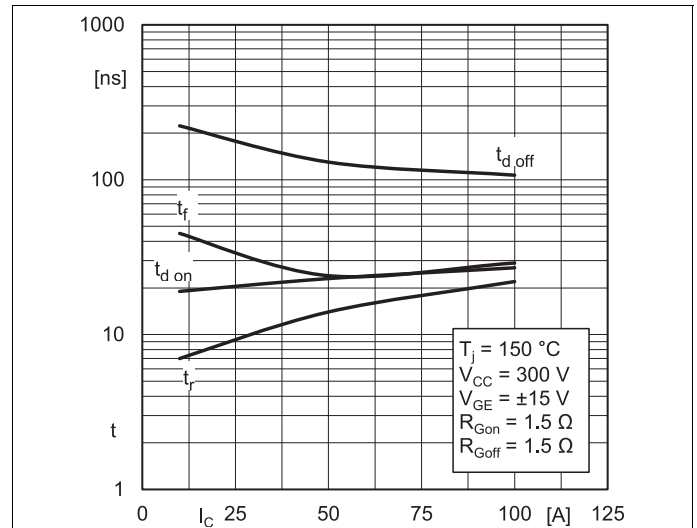


Fig. 7: Typ. IGBT1 switching times vs.  $I_C$

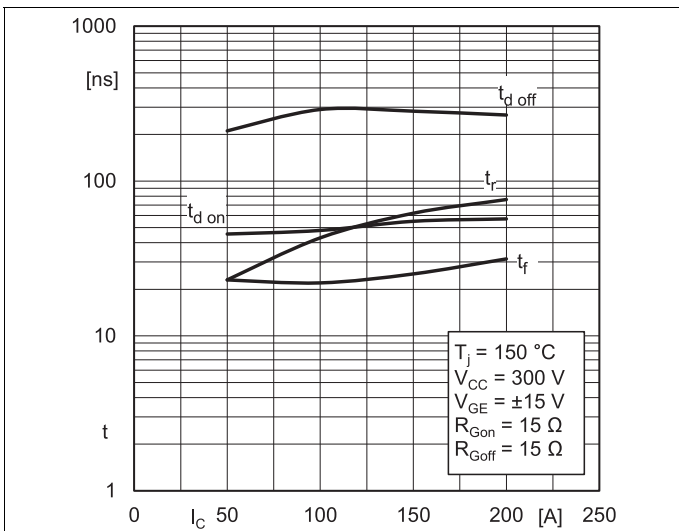


Fig. 7a: Typ. IGBT1 switching times vs.  $I_C$

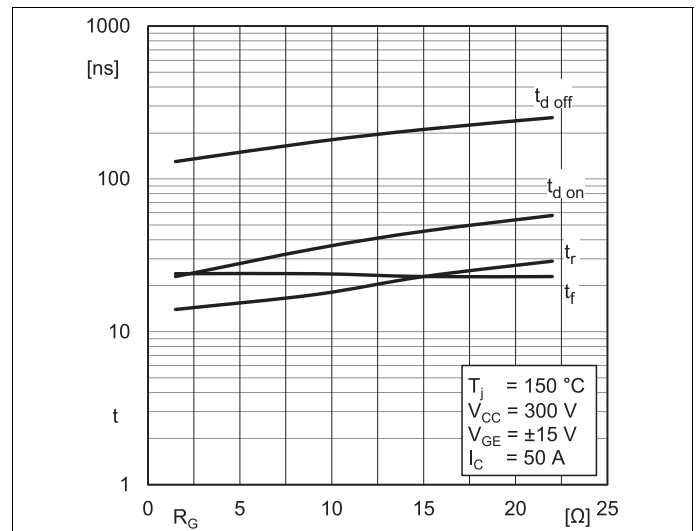


Fig. 8: Typ. IGBT1 switching times vs. gate resistor  $R_G$

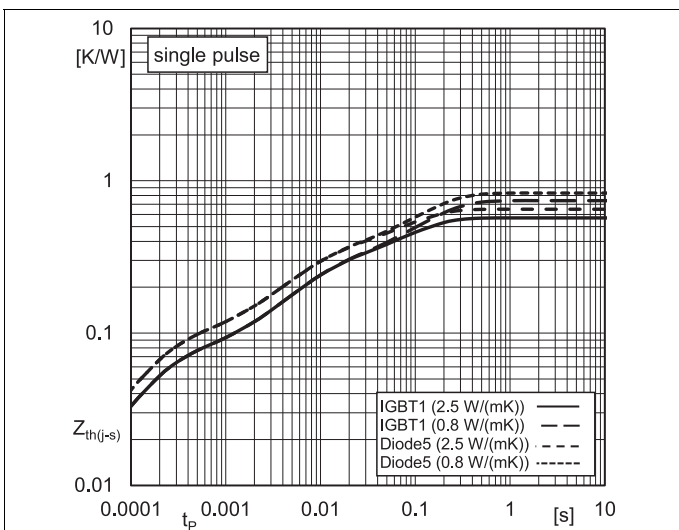


Fig. 9: Typ. transient thermal impedance

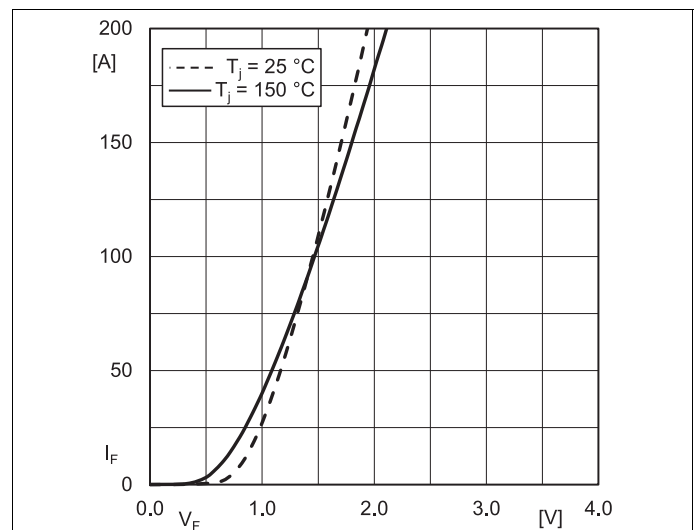


Fig. 10: Typ. Diode5 forward characteristic, incl.  $R_{CC+EE'}$

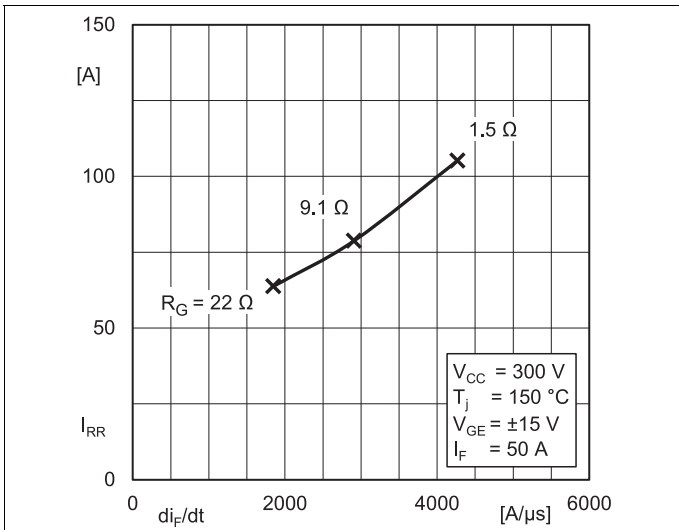


Fig. 11: Typ. Diode5 peak reverse recovery current

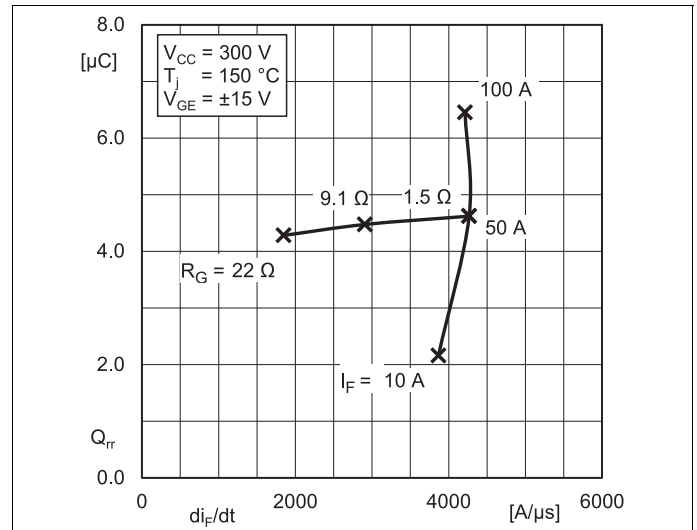


Fig. 12: Typ. Diode5 reverse recovery charge

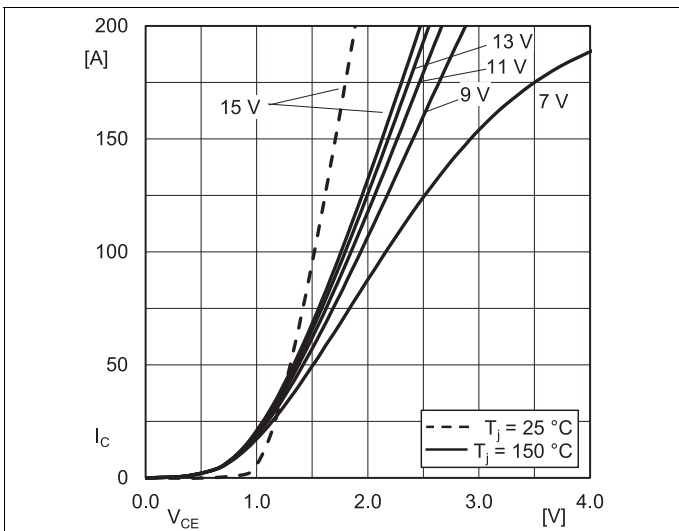


Fig. 13: Typ. IGBT2 output characteristic, incl.  $R_{CC+EE'}$

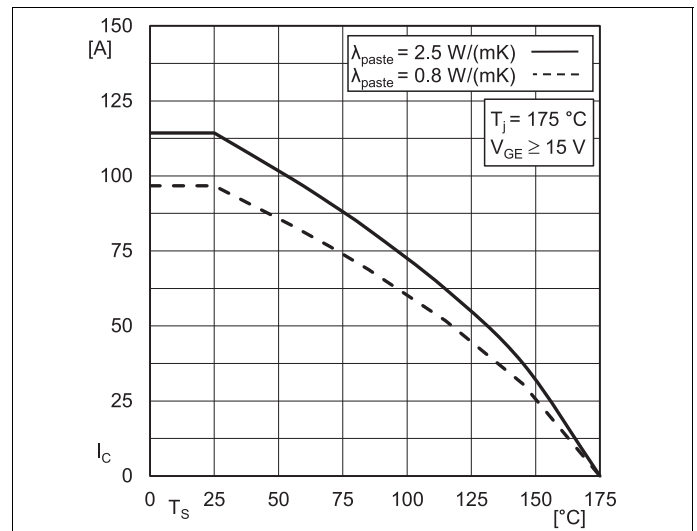


Fig. 14: IGBT2 Rated current vs. Temperature  $I_c = f(T_s)$

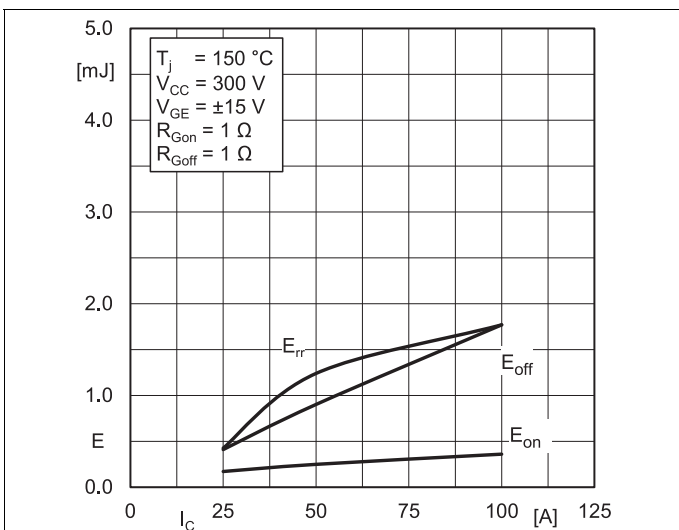


Fig. 15: Typ. IGBT2 & Diode1 turn-on /-off energy =  $f(I_c)$

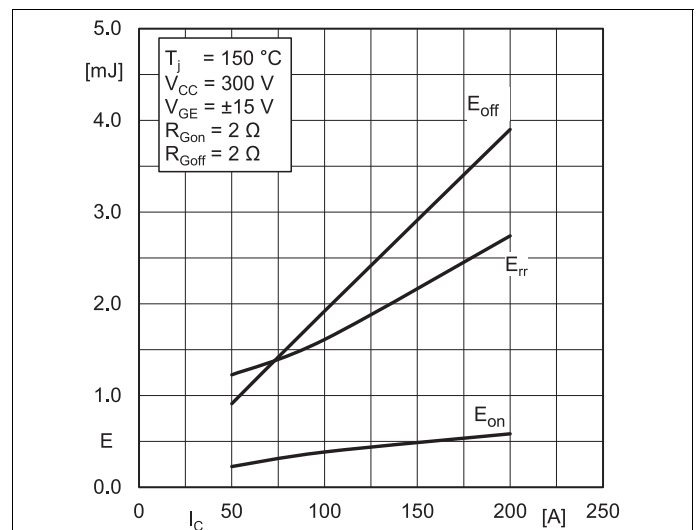


Fig. 15a: Typ. IGBT2 & Diode1 turn-on /-off energy =  $f(I_c)$

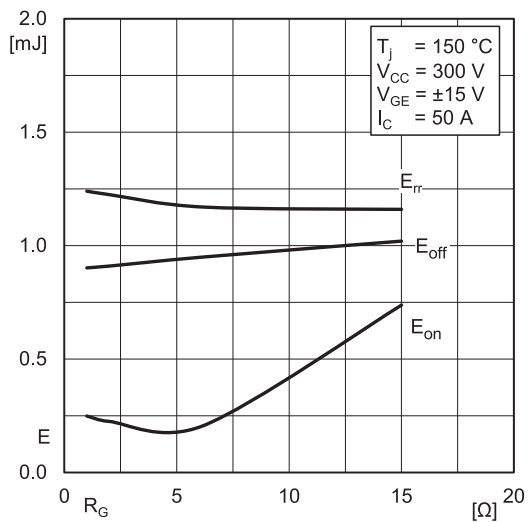


Fig. 16: Typ. IGBT2 & Diode1 turn-on / -off energy =  $f(R_G)$

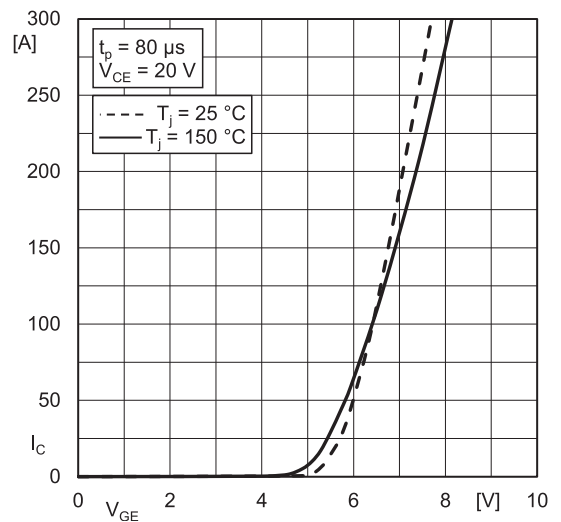


Fig. 17: Typ. IGBT2 transfer characteristic

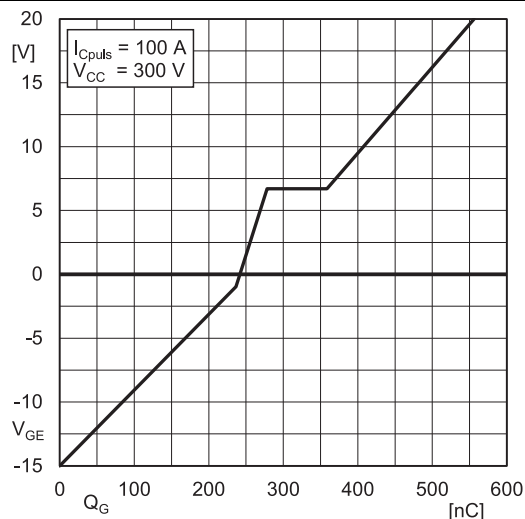


Fig. 18: Typ. IGBT2 gate charge characteristic

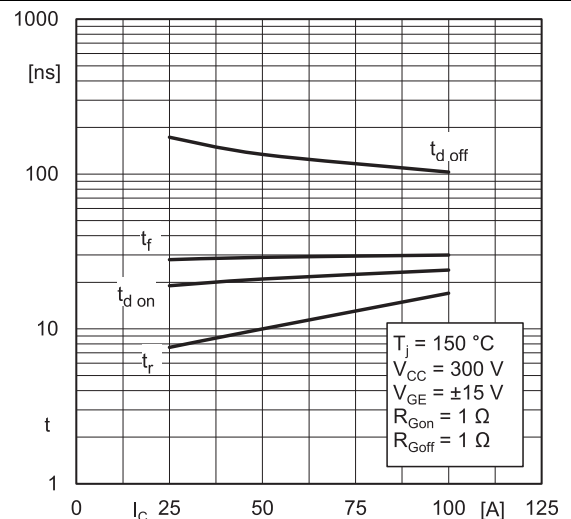


Fig. 19: Typ. IGBT2 switching times vs.  $I_C$

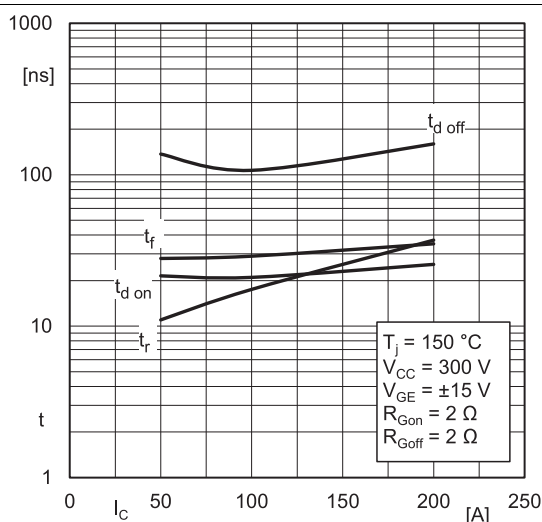


Fig. 19a: Typ. IGBT2 switching times vs.  $I_C$

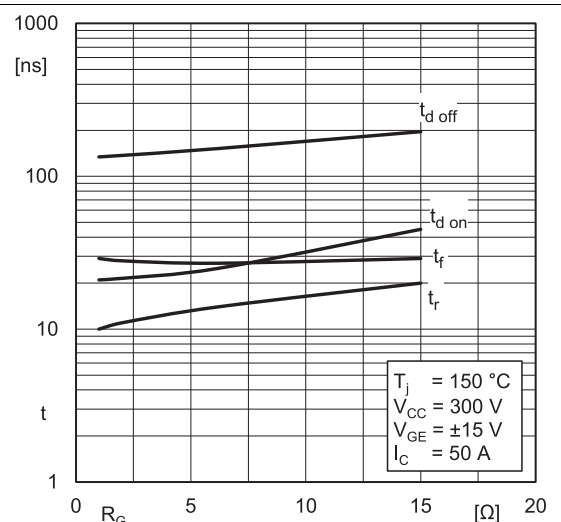


Fig. 20: Typ. IGBT2 switching times vs. gate resistor  $R_G$



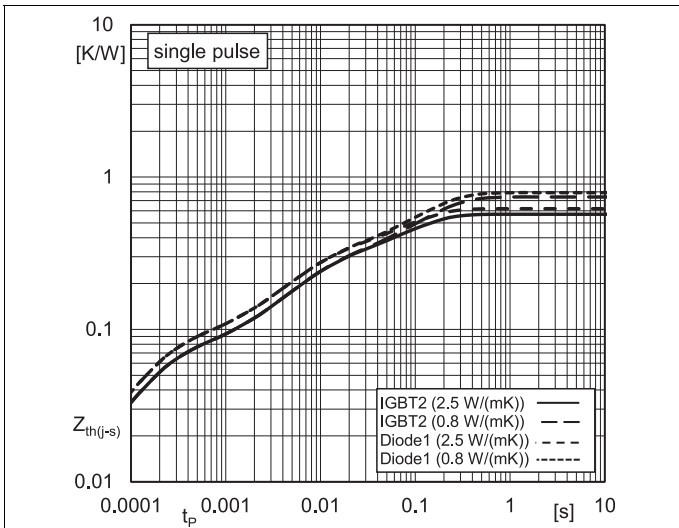


Fig. 21: Typ. transient thermal impedance

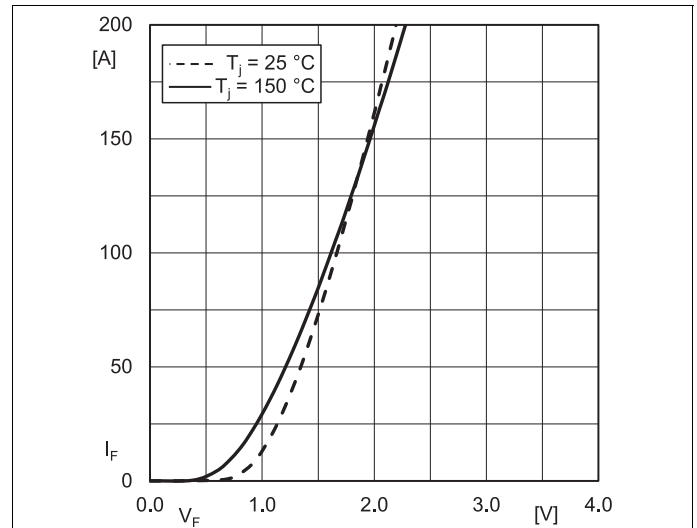


Fig. 22: Typ. Diode1 & Diode2 forward characteristic, incl.  $R_{CC+EE'}$

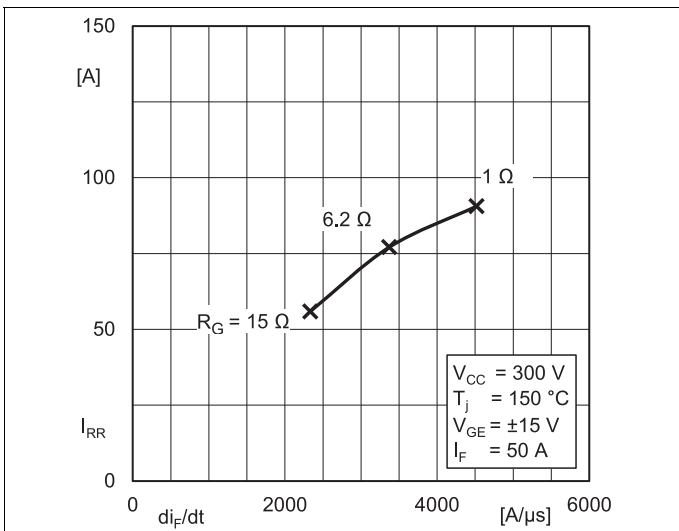


Fig. 23: Typ. Diode1 peak reverse recovery current

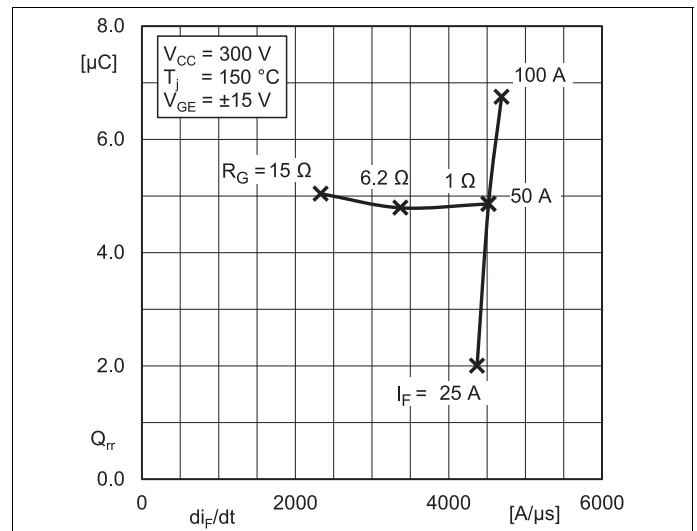
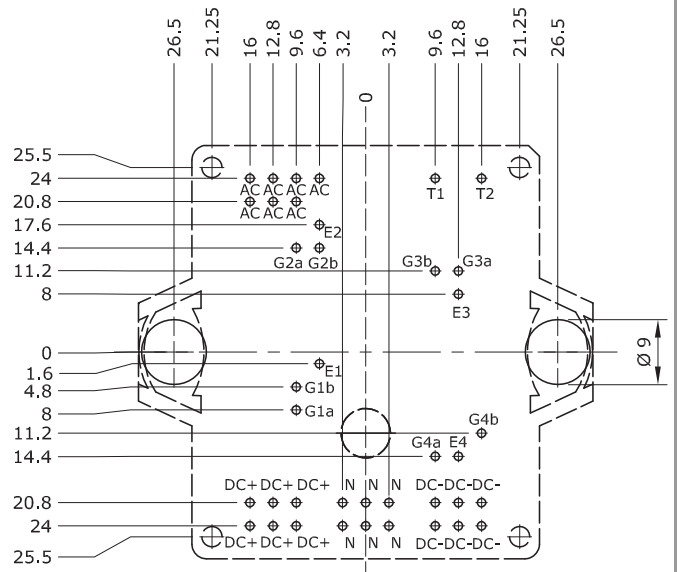
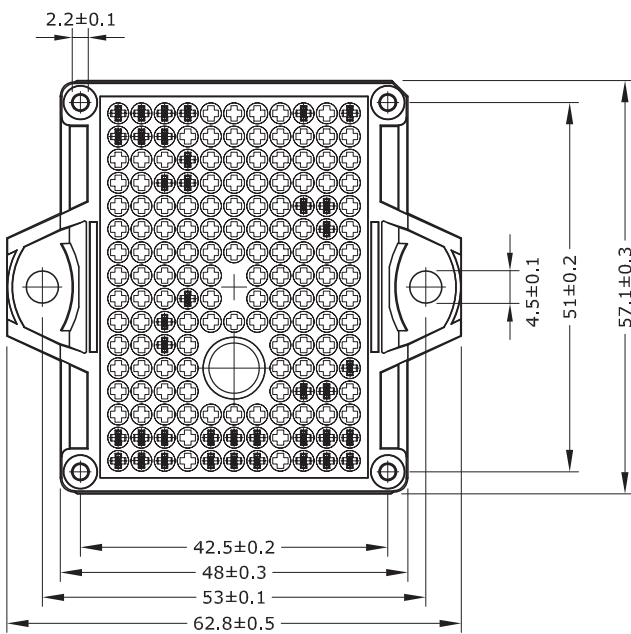
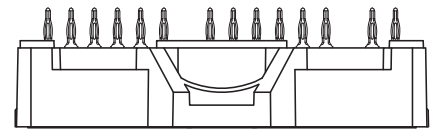
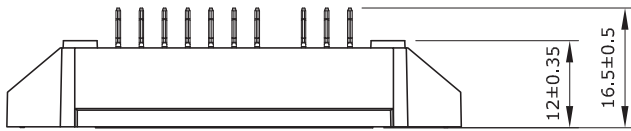


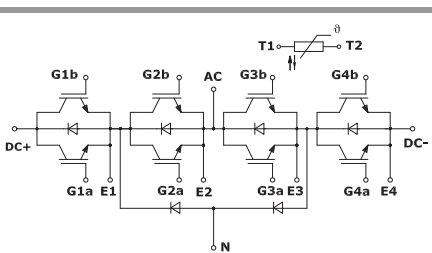
Fig. 24: Typ. Diode1 reverse recovery charge

# SK100MLI07S5TD1E2



- Pin-Grid 3.2 mm
- Tolerance of PCB hole pattern  $\text{⌀} \text{ } \text{⌀}0.1$
- Diameters of drill  $\text{⌀} 1.15\text{mm}$
- Copper thickness in hole 25 - 50  $\mu\text{m}$
- Hole specification for contacts:  
refer to SEMITOP E1/E2 Mounting Instruction

SEMITOP®E2



MLI-T

This is an electrostatic discharge sensitive device (ESDS) due to international standard IEC 61340.

## **\*IMPORTANT INFORMATION AND WARNINGS**

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